

Amendments to the Specification:

Please replace the paragraph beginning at page 1, line 16 with the following amended paragraph:

Fig. 3 shows a configuration of a substrate on which a testing circuit is implemented in a conventional image display device. ~~(For~~ Such a configuration is shown, for example, in Japanese Patent Laid-Open No. 14-116423). The image display device comprises a substrate 301, a source driver circuit 302, a gate driver circuit 303, a pixel 304, a data signal line 305, a scanning line 306, a testing circuit 311, a switch driver circuit 312, an analog switch 313, a testing line 314, and testing terminals 315a and 315b. The substrate 301 mounts the testing circuit 311 and the pixel 304 which are arranged in matrix, and the data signal line (source bus line) 305 and the scanning line (gate bus line) 306 are arranged so as to be orthogonal to each other. The scanning line 306 is connected to the gate driver circuit 303 and the data signal line 305 is connected to the source driver circuit 302.

Please replace the paragraph beginning at page 2, line 29 with the following amended paragraph:

One reason why such a non-display region having a dummy pixel is provided in peripheral portions of a display region is that the peripheral portion of a pixel portion tends to be inhomogeneous compared with the center part thereof in the step for forming a liquid crystal element and a light emitting element in the pixel portion in a flat panel display such as a liquid crystal display device or a light emitting device. ~~(For~~ See, for example, Japanese Patent Laid-Open No. 5-241153).

Please replace the paragraph beginning at page 6, line 22 with the following amended paragraph:

Fig. 1A shows a testing circuit according to the embodiment mode 1 of the invention. The testing circuit comprises a data signal line 101, a scanning line 102, a switching TFT 103, a

driver TFT 104, a capacitor 105, a current supply line 106, a testing cell 107, and a testing line 108. The circuit of Fig. 1A is used for testing data signal lines. The testing circuit comprises a pixel circuit as shown in Fig. 1B and the testing cell 107 corresponds to the pixel circuit. The pixel circuit of Fig. 1B comprises a data signal line 111, a scanning line 112, a switching TFT ~~113~~ 103, a driver TFT ~~114~~ 104, a capacitor ~~115~~ 105, an EL element 116, a current supply line 117, and a power source line 118.